X-Ray Microscopy Techniques

ETH



The Swiss Light Source, Paul Scherrer Institut



- The electrons are accelerated close to the speed of light in a linear accelerator and injected into the storage ring
- Bending magnets or insertion devices (wigglers or undulators) cause electrons to bend or wobble through the section and emit light.



Reference energy: 2.4 GeV Circumference: 288 m Current: 350 mA (400 mA)





- X-rays excite an electron from the core to the valence band
- Relaxation of the electron from the valence to the core level gives:

Soft x-rays: more Auger es

Hard x-rays: more fluorescence

• Therefore different interactions: more than just imaging



- hoton energy
 - Peak corresponds to (set of) transition(s) from core level to valence band

 $\mathbf{E}_{\mathbf{F}}$

 Density of unoccupied states above Fermi level

Each element: own characteristic peaks

energy



PEEM & TXM





Photoemission Electron Microscopy



Slow electrons: mean free path is submono to several monolayers (few nm's)

Surfaces, thin films and interfaces

....consequences for electron optics.

Frithjof Nolting, Swiss Light Source



The Photoemission Electron Microscope (PEEM)



		Slov	v E	lectrons		12
Probe : slow electrons Imaging: high energy electrons (more stable and maintain spatial information)						
t has two fu	nctions: accelerat	ting field d	ue to p	potential & focussir	ng function	
		High voltage:		ge:		
0 eV	20 keV	2	0 keV	• reduced	sensitivity	
				magnetic	fields	
				 reduced spread ar 	energy nd smaller	
Sample High Volta "integral part of lens" Ojective L		ltage / Lens	electron beam diameters		eam ;	
Immersion lens: electrons have before velocity (different way Cathode lens: Sample is cathode electron microscope			e and after the lens different velength) is anode			J. Heyderman
	slow ele high en (more s t has two fu 0 eV 0 eV	slow electrons high energy electrons (more stable and maint t has two functions: accelerat 0 eV 20 keV 20 keV 20 keV electrons have velocity (different s: Sample is cath electron micro	Slov slow electrons high energy electrons (more stable and maintain spatia t has two functions: accelerating field d 0 eV 20 keV 2 ble High Voltage / t of lens" Ojective Lens ns: electrons have before a velocity (different wavel s: Sample is cathode electron microscope is a	Slow E slow electrons high energy electrons (more stable and maintain spatial information in the stress for the stress of	Slow Electrons high energy electrons (more stable and maintain spatial information) t has two functions: accelerating field due to potential & focussir 0 eV 20 keV 20 keV 9 end 0 eV 20 keV 20 keV 9 end 1 do external magnetic 1 reduced a spread ar electron b diameters ns: electrons have before and after the lens differ velocity (different wavelength) s: Sample is cathode electron microscope is anode	Slow Electrons high energy electrons (more stable and maintain spatial information) t has two functions: accelerating field due to potential & focussing function 0 eV 20 keV 20 keV 20 keV ereduced sensitivity to external magnetic fields nee High Voltage / Ojective Lens ns: electrons have before and after the lens different velocity (different wavelength) s: Sample is cathode electron microscope is anode







Energy Filter

Aperture cuts off transmission of electrons with higher energy

Energy distribution is narrowed but transmission (intensity) is reduced. Therefore need to find compromise.



Effect of aperture size on resolution

ETH

- Spatial resolution depends on aperture size limits pencil angle of transmitted electrons and transmission
- Highest resolution is achieved with 12 μm aperture for PEEM2





Spatial Resolution for Magnetic Imaging

PEEM with X-rays: **50-20 nm** spatial resolution

Aberration-corrected instruments using an electron mirror:

SMART (spectromicroscope for all relevant techniques)

- at BESSY II, Berlin, Germany
- collaboration of seven Universities in Germany

PEEM III

- at ALS, Berkeley, USA
- mainly ALS

down to a few nm spatial resolution



Photoemission Electron Microscope Armin Kleibert Carlos Vaz

Fe analyzer elemental composition Intensity [a.u. Ni • chemistry Co structural parameters electronic structure X X X X magnetic properties 700 500 600 800 Photon Energy [eV] topography Magnetic X X lenses e X-rays variable polarization X 20 kV 16° Elemental Contrast

CO Fe La Ti



Photoemission Electron Microscope Armin Kleibert Carlos Vaz





Photoemission Electron Microscope Armin Kleibert Carlos Vaz



X-Ray Magnetic Circular Dichroism (XMCD)



- L-edge absorption in d band transition metal
- Magnetic metal: d valence band split into spin-up and spin-down with different occupation
- Absorption of right/left circular polarisation: light mainly excites spin-up/down photoelectrons
- Spin flips forbidden: measured resonance intensity reflects number of empty d-band states of a given spin
- Can determine sizes and directions of atomic magnetic moment





Magnetostatic or Stray Field Energy

ГН

E



L. J. Heyderman















Ring



Interacting Magnets.....

....with the help of some frogs....!

Interacting Magnetic Frogs





Ring of Nanomagnets





ГН

E





Magnetic Structure: changing phase, changes polarisation



Undulator











Brief Examples

Element specific contrast





Cobalt lines Permalloy film Substrate

Coupling of hard and soft magnetic layer: L. Heyderman, A. Fraile-Rodriguez, A. Hoffmann **Cobalt lines**





Antidot Arrays – Basic Domain Configuration



Remanent Hysteresis Loop in Antidot Arrays



L. J. Heyderman, F. Nolting, D. Backes, S. Czekaj, L. López-Díaz, M. Kläui, U. Rüdiger et al

Cobalt Antidot Arrays



L. J. Heyderman et al., APL (2003), JAP (2004), PRB (2006), JMMM (2007) Mengotti et al., JAP (2007)









A. Farhan et al. Nature Physics (2013), PRL (2013) & PRB (2014)

Iron Nanoparticles Coupled to Cobalt Thin Film

5-25 nm Fe particles/Co thin Film

(C)

Noncollinear alignment for particles > 6 nm



A. Fraile Rodríguez, A. Kleibert, J. Bansmann, A. Voitkans, L. J. Heyderman, and F. Nolting, PRL (2010)



Time Resolved Imaging



- Image excitations in magnetic nanostructures
- Precession frequency & damping
- Pump-probe experiment
- SLS: X-ray stroboscope

J. Raabe et al., Phys. Rev. Lett. 94, 217204 (2005)

ETH Why perform time-resolved imaging?



Are all four feet of a horse off the ground at the same time during a gallop.

The Horse in Motion 1878, animated in 2006, using photos by Eadward Muybridge, Wikipedia



This creates a magnetic field pulse exciting the magnetization.











Permalloy (Ni₈₁Fe₁₉, t=30nm H_p~80 Oe ^{S040906_015}

J. Raabe et al., Phys. Rev. Lett. 94, 217204 (2005)

ETH FEI Py Square: Excitation



- Element selective (multilayer, coupled systems)
- Surface/interface sensitive (sampling depth a few nm)
- Antiferromagnetic and Ferromagnetic domains
- Spatial resolution: 50-20 nm, future aberration corrected: few nm's
- Time resolved measurements
- Temperature 120 K 1000 K
- Submonolayer sensitivity
- Combination with other analytical techniques: LEEM & LEED
- In-situ and ex-situ sample preparation
- Sample size 3 to 15 mm diameter, 0.2 mm 2 mm thick Challenges (limitations):
- UHV compatible (<10⁻⁷ mbar)
- Smooth surface (< 1 μm, hard to say)
- X-ray damage
- Image in applied magnetic field below 50 Oe
- High voltage often leads to discharges (20 keV, at 2 mm distance)
- Charging effects due to electrical insulating sample (can get around this)







A. Hubert and R. Schäfer, Magnetic Domains The Analysis of Magnetic Microstructures

Magnetic Microscopy of Nanostructures An overview of techniques to image the magnetic structure on the nano-scale H. Hopster and H. P. Oepen

Internet, for example:

Techniques to Measure Magnetic Domain Structures, R.J. Celotta, J. Unguris, M.H. Kelley, and D.T. Pierce, Methods in Materials Research (2000)



Comparison Between Different Techniques

- > Contrast Origin: B, M, H_{ext}
- > In Plane or Out-of-Plane components
- > Quantitative or Qualitative
- > Best Resolution, but better Typical Resolution
- > Information depth
- > Sensitivity, Acquisition Time
- > Vacuum Equipment: none, HV, UHV
- Sample requirements: thickness, surface roughness, clean surface, insulators ?
- > In-situ experiments: maximum field, heating, stress
- > Additional information: crystallography, topography, chemical, electronic
- > Commercial Availability, Cost & Complexity Manpower



http://www.fhi-berlin.mpg.de/



B.-S. Kang et al. J Appl. Phys 98 (2005) 093907

Scanning Tunnelling Microscopy

http://lma.unizar.es

- Lorentz Microscopy
- Transmission X-ray Microscopy
- X-ray & Neutron Tomography
- X-ray & Neutron Scattering
- Low Energy Muons



Further Techniques

Muons: L. Anghinolfi et al. Nat. Comm. (Accepted 2015)

X-rays:

- C. Donnelly et al. PRL (2015)
- S. Da Col et al. PRB(R) (2014)

R. Streubel et al. Nat. Comm. (2015)

Neutrons: Manke et al. Nat. Comm. (2010)



X-rays: J. Perron et al. PRB (2013) Neutrons: T. Maurer et al. PRB (2014)



- Scanning Tunnelling Microscopy
- Lorentz Microscopy
- Transmission X-ray Microscopy
- X-ray & Neutron Tomography
- X-ray & Neutron Scattering
- Low Energy Muons



Soft X-ray Science Opportunities Using Diffraction-Limited Storage Rings, ALS 2014 (Scale → Rectangle Size)

4th Generation/DLSR

- (diffraction limited storage ring)
- \rightarrow Multibend Achromat (MBA) accelerator lattices
- \rightarrow Large increase in brightness
 - \rightarrow Several soft bend magnets in each storage ring sector replace 2-3 hard bend magnets
 - \rightarrow smaller horizontal beam dispersion corrected by stronger focusing magnets
 - \rightarrow elliptical profile replaced by compact and nearly circular profiles, with horizontal spatial & angular widths of source decreased by ~ factor of 10 relative to existing sources



Future Challenges

μm



- Currently sub100ps (≈10ps): precession relaxation dynamics (LLG).
- Limited flux of photons: repeatable phenomena (stroboscopic pump-probe).

ns



ps

exchange interactions $t(fs) \sim \frac{4}{E(eV)}$



fs

- Future challenge: fs time scale (exchange interaction time, spin fluctuation time)
- nm spatial resolution in single shot experiment.
- Need high flux (10¹²ph/s) X-ray source
- Lensless imaging and Full-field X-ray microscopy



Peter Fischer, ALS

X-ray Free Electron Lasers

Ultrafast Optical Demagnetisation (100 fs, I=780 nm, 0.2 μJ)





C. von Korff Schmising PRL (2014)
In their conclusions: Ultrafast transport of spin-polarized electrons
→ Domain size controls time scales & spatial extent.
However, exact mechanisms still to be determined.....

Test your understanding.....

Magnetic Force Microscopy, Kerr Microscopy & PEEM Which technique:

- > is sensitive to the stray/external magnetic field?
- > are sensitive samples with out-of-plane M?
- > gives a value of spin and orbital moment?
- > has the best spatial resolution?
- > can be used to look at back surface of sample?
- requires UHV?
- > is difficult for measuring insulators?
- can provide chemical and electronic information? Can you name any other techniques for imaging magnetic domains?